Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10520310	VAN DER MARK ET AL.
Examiner	Art Unit
HENOK G HEYI	2627

SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES		
Search Notes	Date	Examiner
searched class 369/13.13, 13.17, 13.18, 13.19 and 13.33 - text search only (see search history printout) and also consulted primary Tan Dinh.	11/29/2007	нн
Updated search.	07/24/2008	HH
Conducted more search on EAST.	12/05/2008	НН
Updated search.	06/05/2009	HH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
369	13.01	01/13/2010	HH

/HENOK G HEYI/ Examiner.Art Unit 2627	

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